

<b>Notice of References Cited</b>	Application/Control No. 09/348,693	Applicant(s)/Patent Under Reexamination VAN ET TEN ET AL.	
	Examiner Naeem Haq	Art Unit 3625	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,197,005	03-1993	Shwartz et al.	707/2
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*	N	WO 98/02835	01-1998	WIPO	POST et al.	G06F 17/60
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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